VOLUME CONTENTS

VOLUME 28, NUMBER 1 — 1988 — PAGES 1–166

U. Sumita and J. G. Shanthikumar	1	A hybrid simulation/analytic approach for computer communication systems via exponential limit theorems
(Miss) Sharda and Prem Chand Garg	7	A study of a time dependent queueing system with two parallel channels
H. R. Singh, S. K. Singh and S. Shukla	11	A two duplex unit standby system with two types of repair
S. C. Bose, S. Srivastava, C. Shekhar and W. S. Khokle	15	Accuracy of conventional inversion charge modeling in scaled down MOS devices
M. C. Shah and R. Parmar	19	Modified shrinkage technique for estimation of the exponential scale parameter
G. Shankar	23	GERT analysis of sampling plan for system reliability
L. R. Jaisingh	27	Improving the lower bound for the reliability when the strength distribution is gamma and the stress distribution is chi-square
Rong-Hong Jan and Maw-Sheng Chern	43	System reliability design with deteriorative components
Way Kuo and Weixing Zhang	59	Analytical approximation to the queuing model: $(HE_3/HE_3/1)$: $(GD/\infty/\infty)$ for maintainability
G. Schneider	75	Non-metal hermetic encapsulation of a hybrid circuit
D. Kaur	93	On the design of a new arbitration network
S. P. Dokouzgiannis and J. M. Kontoleon	101	Recursive enumeration of state graphs for the reliability evaluation of logic circuits
C. Canali, M. Giannini and E. Zanoni	119	Techniques for latch-up analysis in CMOS IC's based on scanning electron microscopy
	163	New Patents

VOLUME 28, NUMBER 2 — 1988 — PAGES 167–334

	167	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	171	Publications, Notices, Calls for Papers, Etc.
H. Reiche	181	Editorial—Reliability centered maintenance
R. M. Jacobs and L. A. Hoffman	183	Liability aspects of procurement contracts
S. Biswas and V. K. Sehgal	189	On the correlation between inter-arrival delays of shocks
R. Venkatapathi Naidu and S. Mahapatra	193	Fault tolerance in N-MOS random access memories with dynamic redundancy methods
Who Kee Chung	201	A k-out-of-N : G redundant system with dependent failure rates and common-cause failures
G. Brezeanu, D. Dascalu, P. A. Dan, S. Negru and V. Traistaru	205	Changes in electrical characteristics of Al–Ti contacts on silicon

D. Kumar, I. P. Singh and J. Singh	213	Reliability analysis of the feeding system in the paper industry
M. Pandey and S. K. Upadhyay	217	Bayesian inference in mixtures of two exponentials
P. R. Deshmukh, N. K. L. Raja and W. S. Khokle	223	On simulation of resist profiles in electron beam lithography
P. S. Tiwari and K. L. Sharma	229	Microprocessor controlled pre-, post- and instant-gauging with corrective feedback for automatic grinding and cutting machines in line production
D. Eddaifi	235	An efficient solution procedure for transient Markov processes
A. Wild and M. Triantafyllou	243	Electromigration on oxide steps
L. M. Leemis	257	Probabilistic properties of the exponential distribution
Kang W. Lee, Jae J. Suh and Hun Lee	263	Trafficability and reliability analysis for the digital switching network
L. B. Page and J. E. Perry	273	An algorithm for fault-tree probabilities using the factoring theorem
N. Kaio and S. Osaki	287	Optimum planned policies with minimal repair
R. Männer	295	Metastable states in asynchronous digital systems: avoidable or unavoidable?
A. M. Rushdi	309	Effect of statistical dependencies in strict consecutive-*k*-out-of-*n*:F systems
		Technical Note
H. R. Singh and G. Shankar	319	GERT analysis of two-stage attribute sampling plans based on an exponential failure model
	323	Book Reviews
	327	New Patents
	333	Erratum

VOLUME 28, NUMBER 3 1988 PAGES 335–500

	335	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	341	Publications, Notices, Calls for Papers, Etc.
S. Ramamurthy, R. Kumar and D. N. Singh	345	Printability of mask defects in negative resist projection photolithography
V. M. Cătuneanu, C. Moldovan, Fl. Popenţiu and M. Gheorghiu	353	Optimum system availability and spare allocation
M. Sharafali, R. Natarajan and P. R. Parthasarathy	359	A complex two unit system with stochastic demand
A. M. Eydgahi and H. Singh	363	Systolic array for VLSI implementation of realization techniques
K. Shankar Bhat, M. Gururajan and P. Nayak	369	A study of a 2-unit system with 'random breakdown' of the repair facility
A. A. Al-Ali and K. Murari	373	One unit reliability system subject to random shocks and preventive maintenance
V. N. Rai, V. P. Gupta and S. K. Saxena	379	Modified preliminary test estimator for average life in one parameter exponential distribution
S. K. Singh, S. Shukla and A. Shukla	383	Cost–benefit analysis of a system with inspection, replacement and two types of repair

Who Kee Chung	391	An availability analysis of a k-out-of-N:G redundant system with dependant failure rates and common-cause failures
C. G. Guy, C. A. Njinda, K. J. Steptoe and G. Santoro	395	An automatic concurrent error detecting tool for PLA generation
D. Eddaifi	407	Time-dependent benefit analysis of two competing fault-tolerant systems
Y. S. Sherif and B. J. Matt	419	Computer networks and distributed systems
L. R. Jaisingh	469	Competing risks in parallel and series systems
C. T. Lin, B. S. Duran and T. O. Lewis	487	Estimating lower confidence limits on system reliability using a Monte-Carlo technique on binomial data
	495	Book Reviews
	497	New Patents

VOLUME 28, NUMBER 4 1988 PAGES 501–672

	501	Publications, Notices, Calls for Papers, Etc.
R. M. Jacobs	507	Conference Report: The 34th Reliability and Maintainability Symposium
J. L. Roca	511	Testing hypotheses on correctness software estimation
C. Mohan and K. Shanker	513	Reliability optimization of complex systems using random search technique
K. K. Das and D. Acharya	519	Optimal replacement policy for induced draft fans
P. P. Gupta, A. Kumar and G. S. Srivastava	525	Operational behaviour of a complex system operating under different weather conditions
R. K. Bhan and K. C. Chhabra	531	D.C. leakage currents in 1,1,1-trichloroethane oxides
N. A. Mokhles and E. H. Saleh	535	Reliability analysis of a k-out-of-N:F repairable system with dependent units
S. P. Dokouzgiannis and J. M. Kontoleon	541	Determination of combinational logic circuit reliability through generation of fault diagnosis tests
V. M. Cătuneanu, C. Moldovan, Fl. Popenţiu and M. Gheorghiu	547	Optimal software release policies using SLUMT
Z. M. Wojcik and B. E. Wojcik	551	Order-clustering of secant tips into edges for positioning of semiconductor structures
A. Rangan and R. E. Grace	563	On a class of optimal preventive replacement policies of systems subject to shocks
N. Ebrahimi	569	Estimating the mean life time when new is better than used in expectation
B. S. Dhillon and S. N. Rayapati	573	Human performance reliability modelling
W. H. Iskander and R. S. Nutter Jr	581	Methodology development for safety and reliability analysis for electrical mine monitoring systems
R. Osredkar	599	A study of the imidization kinetics of polyimide resin curing
K. Goser	605	Tunneling and thermal noise as limiting factors in microelectronics
D. R. Wingo	613	Parametric point estimation for a doubly-truncated Weibull distribution

G. G. Pullum, M. Chown and G. A. Whitmore	619	Reliability analysis of a multipath switching network
K. Yasui, T. Nakagawa and S. Osaki	635	A summary of optimum replacement policies for a parallel redundant system
B. Pešić, S. Dimitrijev and N. Stojadinović	643	Sudden failures associated with the gate oxide of CMOS transistors
		Technical Note
K. K. Govil	649	A linear analytical model for cost vs. repair time
	651	Book Reviews
	653	World Abstracts on Microelectronics and Reliability
	665	New Patents
	671	Errata

VOLUME 28, NUMBER 5 1988 PAGES 673–840

	673	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	677	Publications, Notices, Calls for Papers, Etc.
Guo Tong De	687	Letter to the Editor—Comments on "Stochastic analysis of a two unit cold standby system with preparation time for repair"
M. C. Shah, R. Parmar and V. P. Gupta	689	Some techniques of minimum mean square error estimation
Tuyet-Lan Tran and Y. S. Sherif	693	Software metrics: measuring the progress of software development
R. C. Tiwari and J. N. Zalkikar	703	Testing whether F is "more IFRA than is G"
Guang-Bo Gao and Xiang Gui	713	Reliability physics as a new discipline
B. E. Wojcik	721	A probabilistic model of quality control in microelectronics
M. Mahmoud, N. A. Mokhles and E. H. Saleh	729	Probabilistic analysis of K-out-of-N:F three state-unit redundant system with common-cause failure and replacements
L. A. Baxter	743	Some criteria for reliability growth
J. Card and Wai Chan	751	Estimation of the Weibull renewal function
G. L. Schnable and G. A. Swartz	757	In-process voltage stressing to increase reliability of MOS integrated circuits
J. M. Kontoleon and D. Mandaltsis	783	An improved method of enumerating all trees and minimal paths in a graph using Petri nets
L. B. Page and J. E. Perry	793	Hypermedia and network reliability
Kecheng Shen	801	On the relationship between component failure rate and stress–strength distributional characteristics
T. Wada, Y. Kobayashi, N. Maeda, M. Sugimoto and T. Ajiki	813	Study of acceleration factor on moisture resistance test of plastic encapsulated semiconductor devices
	821	Book Reviews *Chemical Vapor Deposition for Microelectronics* *Modern Techniques of Surface Science* *Introduction to Microelectronic Fabrication*
	825	World Abstracts on Microelectronics and Reliability
	837	New Patents

VOLUME 28, NUMBER 6 1988 PAGES 841–1002

	841	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	845	Publications, Notices, Calls for Papers, Etc.
	855	Memo to all Indian Authors
Zhibang Zhou	857	MTBRD analysis of fail-safe systems
Zhibang Zhou and Benchu Wang	861	MTBRD evaluation of an actual fail-safe system
Huang Xizi	865	Non-linear regression for predicting software reliability
D. Kumar, J. Singh and I. P. Singh	867	Availability of the feeding system in the sugar industry
K. C. Madan	873	A cyclic queueing system with three servers and optional two-way feedback
R. Venkatapathi Naidu and S. Mahapatra	877	Power reduction methods for NMOS dynamic random access memories
A. Srivastava	885	Device failure analysis in VLSI circuits due to missing flashes in mask fabrication process—a case study
Jinhua Cao	889	Reliability analysis of a repairable system in a changing environment subject to a general alternating renewal process
B. N. Shetty, G. S. Sekhon, O. P. Chawla and K. C. Kurien	893	Optimization of maintenance facility for a repairable system subject to availability constraint
M. A. W. Mahmoud	897	On a two-unit cold standby redundant system with random switching time
M. T. Wells and R. C. Tiwari	901	Testing whether F is "more NBU" than is G with randomly censored data
D. K. Dey, Anita Singh and Ashok Singh	909	Estimation of series system reliability for exponentially distributed component life times
L. H. Canter and Y. S. Sherif	919	Parallel processing, distributed systems and local area networks
B. N. Pandey, H. J. Malik and R. Srivastava	929	Shrinkage testimators for the variance of a normal distribution at single and double stages
A. M. Rushdi and K. F. Kafrawy	945	Uncertainty propagation in fault-tree analyses using an exact method of moments
D. Mandaltsis and J. M. Kontoleon	967	On the determination of overall computer network reliability with m-level hierachical routing
V. Obac Roda	979	The hybrid approach for improving the reliability of ring systems
	991	Book Reviews *Sensors and Transducers* *Tolerance Design of Electronic Circuits* *Electronic Alarm Circuits Manual* *Practical Electronics Handbook—Second Edition* *Handbook of Contamination Control in Microelectronics* *VLSI Electronics—Microstructure Science* *LSI Interfacing* *Rigid-Flex Printed Wiring Design for Production Readiness* *The Conquest of the Microchip*
	999	New Patents
	i	Title Section, Volumen Contents and Author Index, Volume 28, 1988